

Materials List for:

Quantitative Hardness Measurement by Instrumented AFM-indentation

Arnaud Caron¹

¹School of Energy, Materials and Chemical Engineering, KoreaTech, Korea University of Technology and Education

Correspondence to: Arnaud Caron at arnaud.caron@koreatech.ac.kr

URL: <https://www.jove.com/video/54706>

DOI: [doi:10.3791/54706](https://doi.org/10.3791/54706)

Materials

Name	Company	Catalog Number	Comments
AFM XE-100	Park Instruments	discontinued	Atomic force microscope
CDT-NCLR	NanoSensors	CDT-NCLR	Conductive diamond coated non-contact lever
100 nm thick Au(111) thin film on Mica	Phasis	20020011	atomically smooth gold thin film